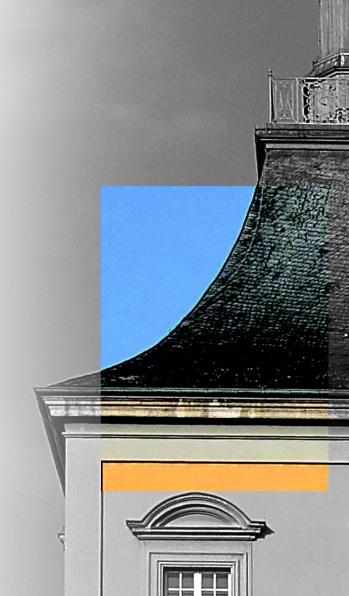


# Lab Framework

PXD Workshop and 24th International Workshop on DEPFET Detectors and Applications 17.05.2022

G. Giakoustidis\*

Physikalisches Institut der Universität Bonn





# **OVERVIEW**

- Short recap PXD Workshop 01.2022
- Updates regarding KEK
- More general updates
- Todo list



### **RECAP PXD WS 01.2022**

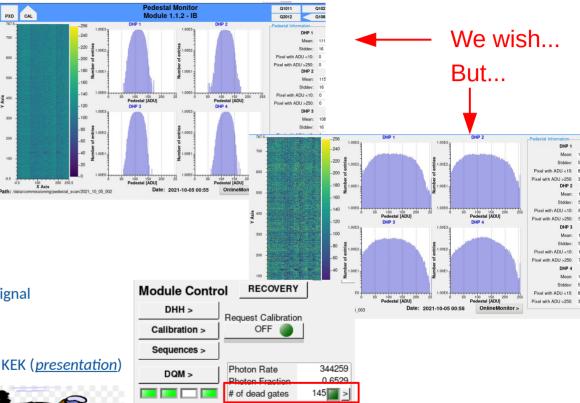
- Lab Framework updates regarding KEK
  - Modification of the Power-up Sequence (PR1, PR2, PR3, presentation)
  - Scheduling full calibration if the commitID is changed (PR)
  - Special handling of DHP monitoring and temperature measurement when setting DCD parameters → no OVPs (PR)
  - The functionality of the DHP Register Monitor can be manually paused (it is now paused during any calibration type) (PR)
  - Speedup (~10%) DHH data recording by fixing the waiting time (<u>PR</u>)
- More general updates
  - Added checking constraints when setting PVs (PR)
  - Ramping of PS during a calibration (<u>PR</u>)
  - More comprehensive plots from the offset scan (<u>discussion</u>, <u>PR</u>)



### **UPDATES REGARDING KEK**

- Offsets calibration investigation (<u>presentation</u>, <u>JIRA ticket</u>)
  - New approaches were tried
  - Algorithm not robust enough
  - Raw pedestals too wide and wider than the dynamic range
  - Take offsets with lower gain and operate with default gain
  - Operate with lower gain
    - ✓ More pixels into the dynamic range and able to measure signal
    - Reduced efficiency and SNR
- Investigations on improving the dead gate detection algorithm at KEK (presentation)
- Faster pedestal upload by 12 seconds (PR)



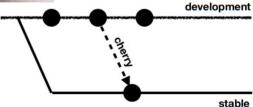




#### **MORE GENERAL UPDATES**

- Calibration class implementation (<u>PR</u>, <u>presentation</u>)
  - Unify the calibration scripts (measurement, analysis and update to configDB)
  - Reduce duplicated code in the framework
  - Many calibrations have already migrated to this scheme
- Improvements in PXD9 module characterization (mass-testing) for PXD2
  - Additional calibrations (g<sub>m</sub>, V<sub>TH</sub>, ADC transfer curves using external current source)
  - Handbook update for even safer module operation
  - Additional interlock based on temperature and humidity monitoring available (installed and stably running in Bonn)
- New branching model introduced (<u>presentation</u>)
  - Three branches: 1) **development** (default), 2) **main** (used for mass-testing), 3) **kek**
  - Feature branches are merged to development
  - When development stable (new release) → merge to main







# **TODO LIST**

- Set DCD pixel chain to a defined value during TURNINGON (in progress)
- Fix remaining ADC scan issues with DHC setups
- Further automatization during maintenance days and half-shell commissioning
- More technical stuff...



